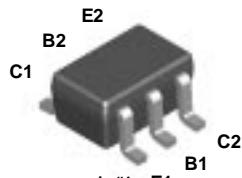


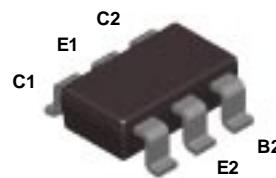


FFB3904



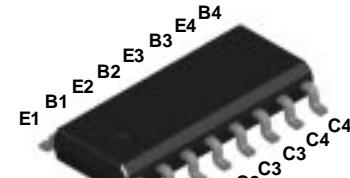
SC70-6
Mark: .1A

FMB3904



SuperSOT™-6
Mark: .1A

MMPQ3904



SOIC-16

NPN General Purpose Amplifier

This device is designed as a general purpose amplifier and switch. The useful dynamic range extends to 100 mA as a switch and to 100 MHz as an amplifier. Sourced from Process 23.

Absolute Maximum Ratings*

$T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Value	Units
V_{CEO}	Collector-Emitter Voltage	40	V
V_{CBO}	Collector-Base Voltage	60	V
V_{EBO}	Emitter-Base Voltage	6.0	V
I_C	Collector Current - Continuous	200	mA
T_J, T_{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

* These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150 degrees C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics

$T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Characteristic	Max			Units
		FFB3904	FMB3904	MMPQ3904	
P_D	Total Device Dissipation Derate above 25°C	300 2.4	700 5.6	1,000 8.0	mW mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient Effective 4 Die Each Die	415	180	125 240	°C/W °C/W °C/W

NPN Multi-Chip General Purpose Amplifier

(continued)

Electrical Characteristics $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS						
$V_{(\text{BR})\text{CEO}}$	Collector-Emitter Breakdown Voltage	$I_C = 1.0 \text{ mA}, I_B = 0$	40			V
$V_{(\text{BR})\text{CBO}}$	Collector-Base Breakdown Voltage	$I_C = 10 \mu\text{A}, I_E = 0$	60			V
$V_{(\text{BR})\text{EBO}}$	Emitter-Base Breakdown Voltage	$I_E = 10 \mu\text{A}, I_C = 0$	6.0			V
I_{BL}	Base Cutoff Current	$V_{CE} = 30 \text{ V}, V_{EB} = 0$			50	nA
I_{CEX}	Collector Cutoff Current	$V_{CE} = 30 \text{ V}, V_{EB} = 0$			50	nA
ON CHARACTERISTICS*						
h_{FE}	DC Current Gain	$I_C = 0.1 \text{ mA}, V_{CE} = 1.0 \text{ V}$	40			
		$I_C = 1.0 \text{ mA}, V_{CE} = 1.0 \text{ V}$	70			
		$I_C = 10 \text{ mA}, V_{CE} = 1.0 \text{ V}$	100			
		$I_C = 50 \text{ mA}, V_{CE} = 1.0 \text{ V}$	60			
		$I_C = 100 \text{ mA}, V_{CE} = 1.0 \text{ V}$	30			
$V_{CE(\text{sat})}$	Collector-Emitter Saturation Voltage	$I_C = 10 \text{ mA}, I_B = 1.0 \text{ mA}$			0.2	V
		$I_C = 50 \text{ mA}, I_B = 5.0 \text{ mA}$			0.3	V
$V_{BE(\text{sat})}$	Base-Emitter Saturation Voltage	$I_C = 10 \text{ mA}, I_B = 1.0 \text{ mA}$	0.65		0.85	V
		$I_C = 50 \text{ mA}, I_B = 5.0 \text{ mA}$			0.95	V
SMALL SIGNAL CHARACTERISTICS						
f_T	Current Gain - Bandwidth Product	$I_C = 10 \text{ mA}, V_{CE} = 20 \text{ V}, f = 100 \text{ MHz}$		450		MHz
C_{obo}	Output Capacitance	$V_{CB} = 5.0 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$		2.5		pF
C_{ibo}	Input Capacitance	$V_{EB} = 0.5 \text{ V}, I_C = 0, f = 1.0 \text{ MHz}$		6.0		pF
NF	Noise Figure (except MMPQ3904)	$I_C = 100 \mu\text{A}, V_{CE} = 5.0 \text{ V}, R_S = 1.0 \text{k}\Omega, f = 10 \text{ Hz to } 15.7 \text{ kHz}$		2.0		dB
SWITCHING CHARACTERISTICS						
t_d	Delay Time	$V_{CC} = 3.0 \text{ V}, V_{BE} = 0.5 \text{ V}, I_C = 10 \text{ mA}, I_{B1} = 1.0 \text{ mA}$		18		ns
t_r	Rise Time			20		ns
t_s	Storage Time	$V_{CC} = 3.0 \text{ V}, I_C = 10 \text{ mA}, I_{B1} = I_{B2} = 1.0 \text{ mA}$		150		ns
t_f	Fall Time			25		ns

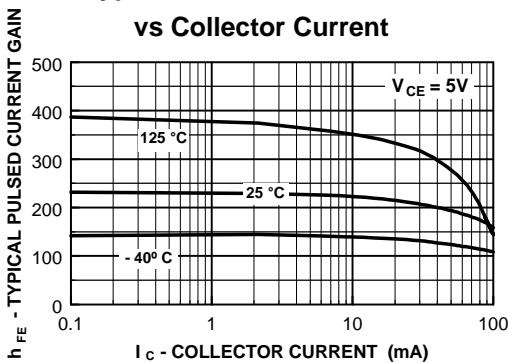
* Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $\leq 2.0\%$

NPN Multi-Chip General Purpose Amplifier

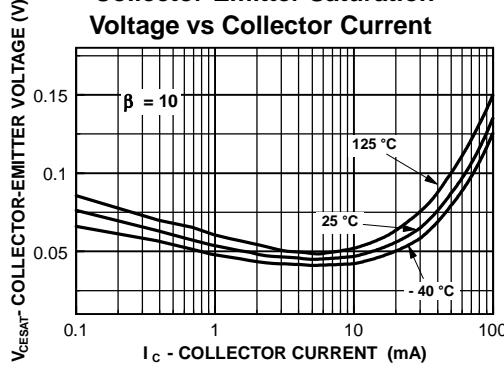
(continued)

Typical Characteristics

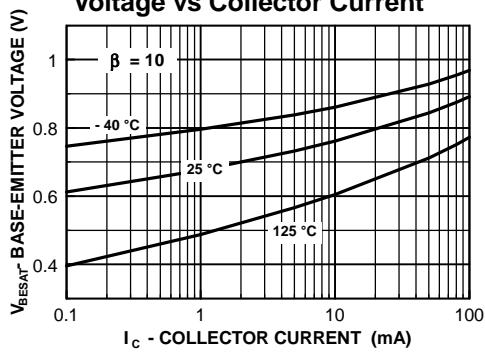
**Typical Pulsed Current Gain
vs Collector Current**



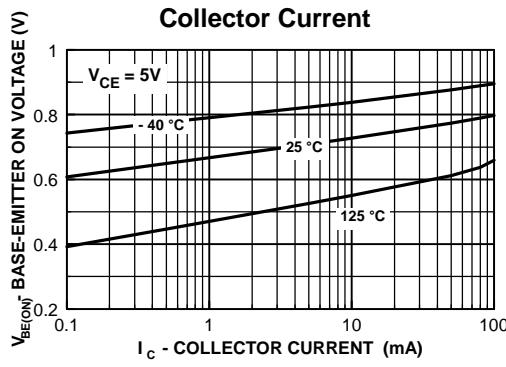
**Collector-Emitter Saturation
Voltage vs Collector Current**



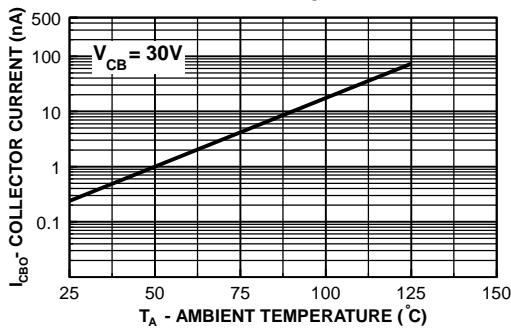
**Base-Emitter Saturation
Voltage vs Collector Current**



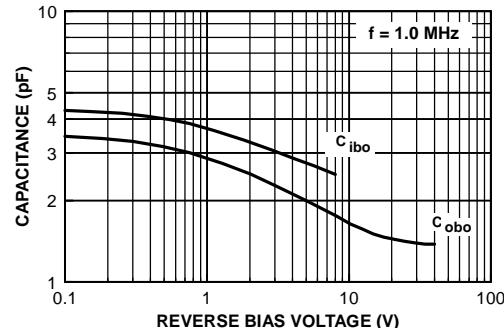
**Base-Emitter ON Voltage vs
Collector Current**



**Collector-Cutoff Current
vs Ambient Temperature**



**Capacitance vs
Reverse Bias Voltage**

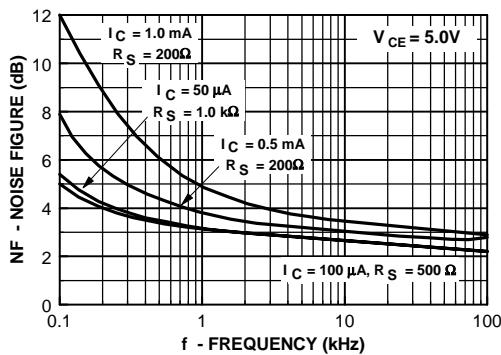


NPN Multi-Chip General Purpose Amplifier

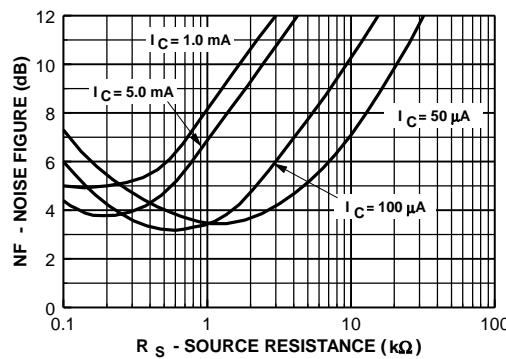
(continued)

Typical Characteristics (continued)

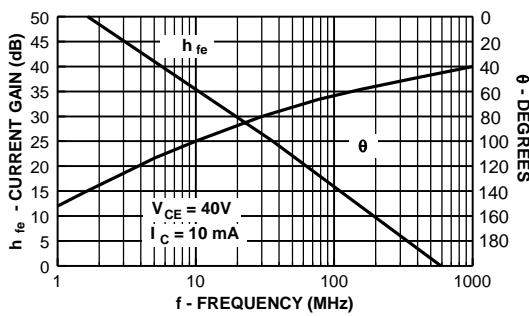
Noise Figure vs Frequency



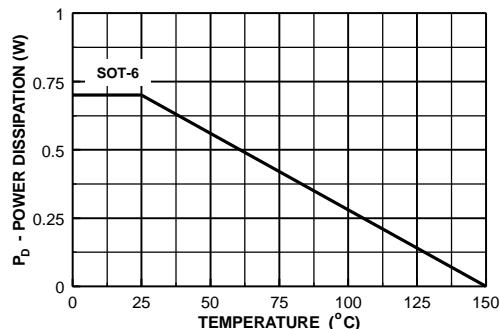
Noise Figure vs Source Resistance



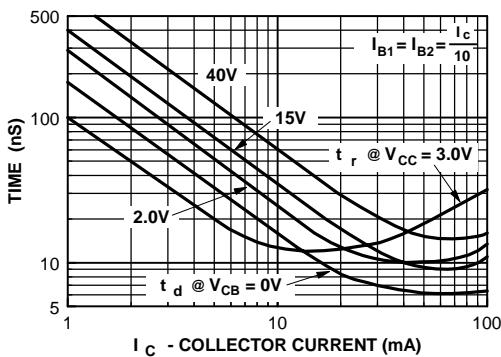
Current Gain and Phase Angle vs Frequency



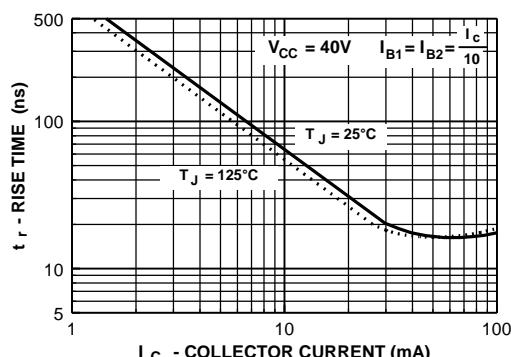
Power Dissipation vs Ambient Temperature



Turn-On Time vs Collector Current



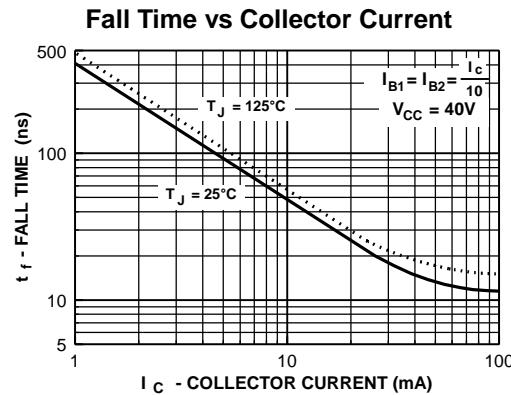
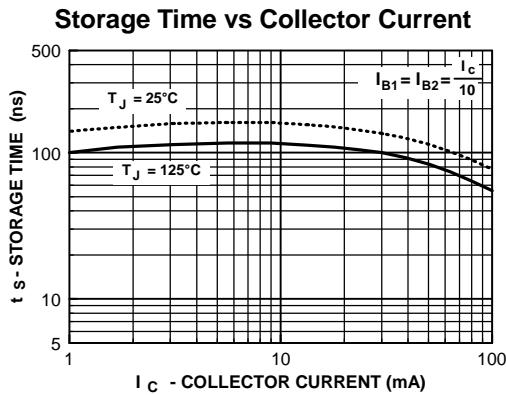
Rise Time vs Collector Current



NPN Multi-Chip General Purpose Amplifier

(continued)

Typical Characteristics (continued)



Test Circuits

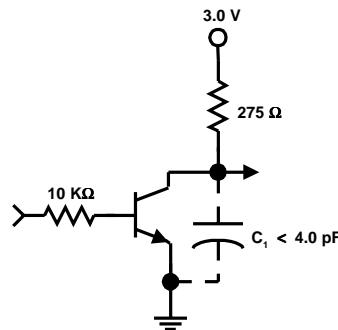
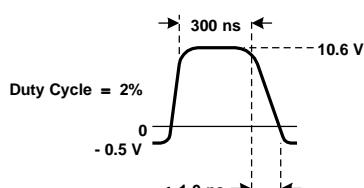


FIGURE 1: Delay and Rise Time Equivalent Test Circuit

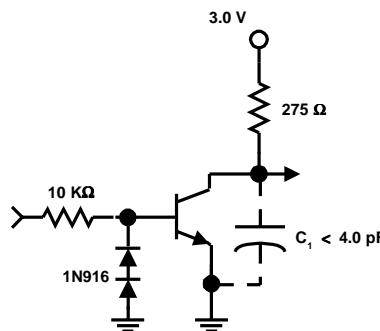
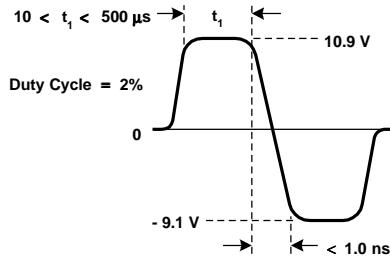


FIGURE 2: Storage and Fall Time Equivalent Test Circuit